Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/825,397	CHANG, LEON F.
Examiner	Art Unit
Hanh Nauven	2668

SEARCHED				
Class	Subclass	Date	Examiner	
370	400	10/11/2005	HN	
	389			
	314			
	356			
	401			
	395.5			
	395.53			
	395.6			
	395.61			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
370	395.6	10/5/2005	HN	
	352			
	401			

	(INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
east	10/5/2005	HN	
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